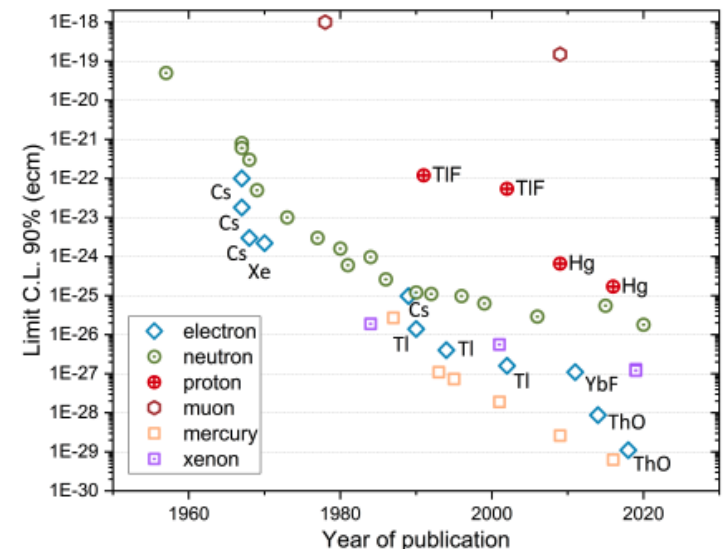
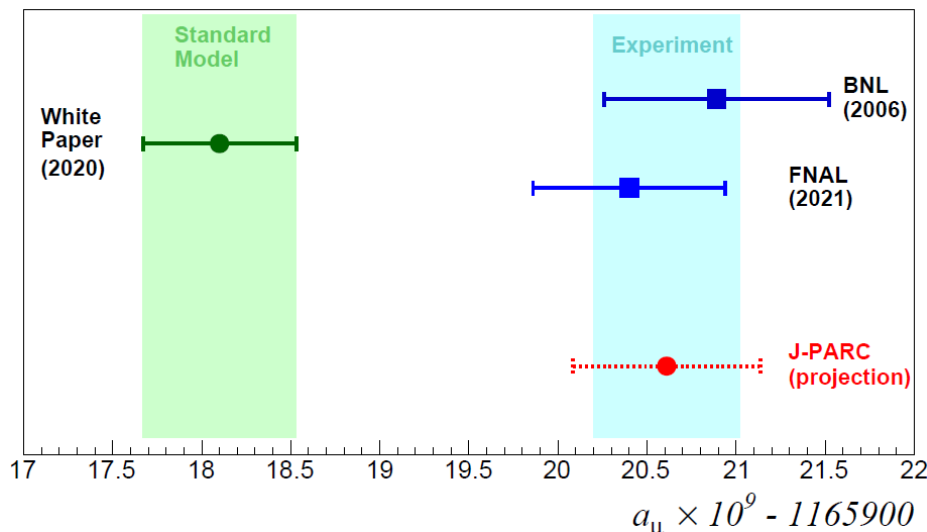


# Silicon strip detector for muon $g-2$ /EDM experiment at J-PARC

S.Ogawa (Kyushu Univ.)  
on behalf of the J-PARC  
muon  $g-2$ /EDM collaboration

@Vertex 2022

- Muon anomalous magnetic moment (g-2)
  - 4.2  $\sigma$  tension b/w measurement & prediction
  - Measurement:  $116592061(41) \times 10^{-11}$  (350 ppb)
  - SM prediction:  $116591810(43) \times 10^{-11}$  (370 ppb)
  - This can be a contribution from new physics.  
Another measurement by an independent strategy is desired.
- Muon EDM
  - Upper limit given by BNL:  $1.8 \times 10^{-19} \text{ e} \cdot \text{cm}$  (95% C.L.)
  - Indicates CP violation in lepton sector.



- Muon g-2/EDM can be measured from spin precession of muon in a uniform B-field.
  - time dependent spin information reconstructed from decay positron energy/momentum.

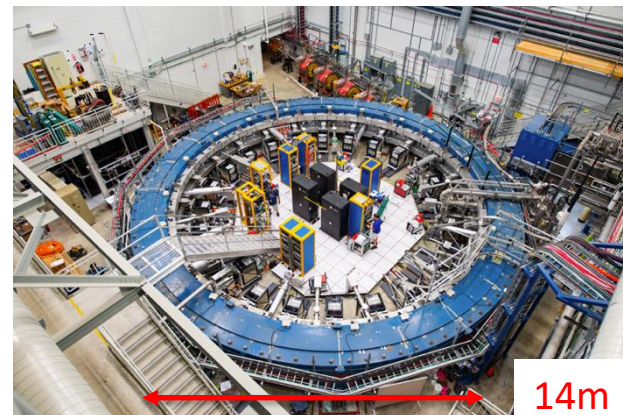
$$\vec{\omega}_a + \vec{\omega}_\eta = -\frac{e}{m_\mu} \left[ \underbrace{a_\mu \vec{B}}_{\text{g-2}} - \left( a_\mu - \frac{1}{\gamma^2 - 1} \right) \frac{\vec{\beta} \times \vec{E}}{c} + \underbrace{\frac{\eta}{2} \left( \vec{\beta} \times \vec{B} + \frac{\vec{E}}{c} \right)}_{\text{EDM}} \right]$$

## BNL/ FNAL experiment

$$\vec{\omega}_a + \vec{\omega}_\eta = -\frac{e}{m_\mu} \left[ a_\mu \vec{B} - \left( a_\mu - \frac{1}{\gamma^2 - 1} \right) \frac{\vec{\beta} \times \vec{E}}{c} + \frac{\eta}{2} \left( \vec{\beta} \times \vec{B} + \frac{\vec{E}}{c} \right) \right]$$

= 0

- **Measurement at magic gamma momentum.**
  - to cancel out 2<sup>nd</sup> term.
  - **p = 3.1 GeV/c, ϕ: 14 m at B = 1.45 T**
- Strong electric field focusing.



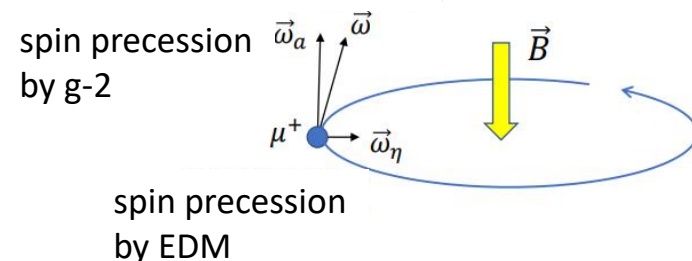
14m

## J-PARC experiment

- **Measurement at  $\vec{E} = 0$ .**

- Beam storage by weak focusing B-field
- Utilize low emittance muon beam.

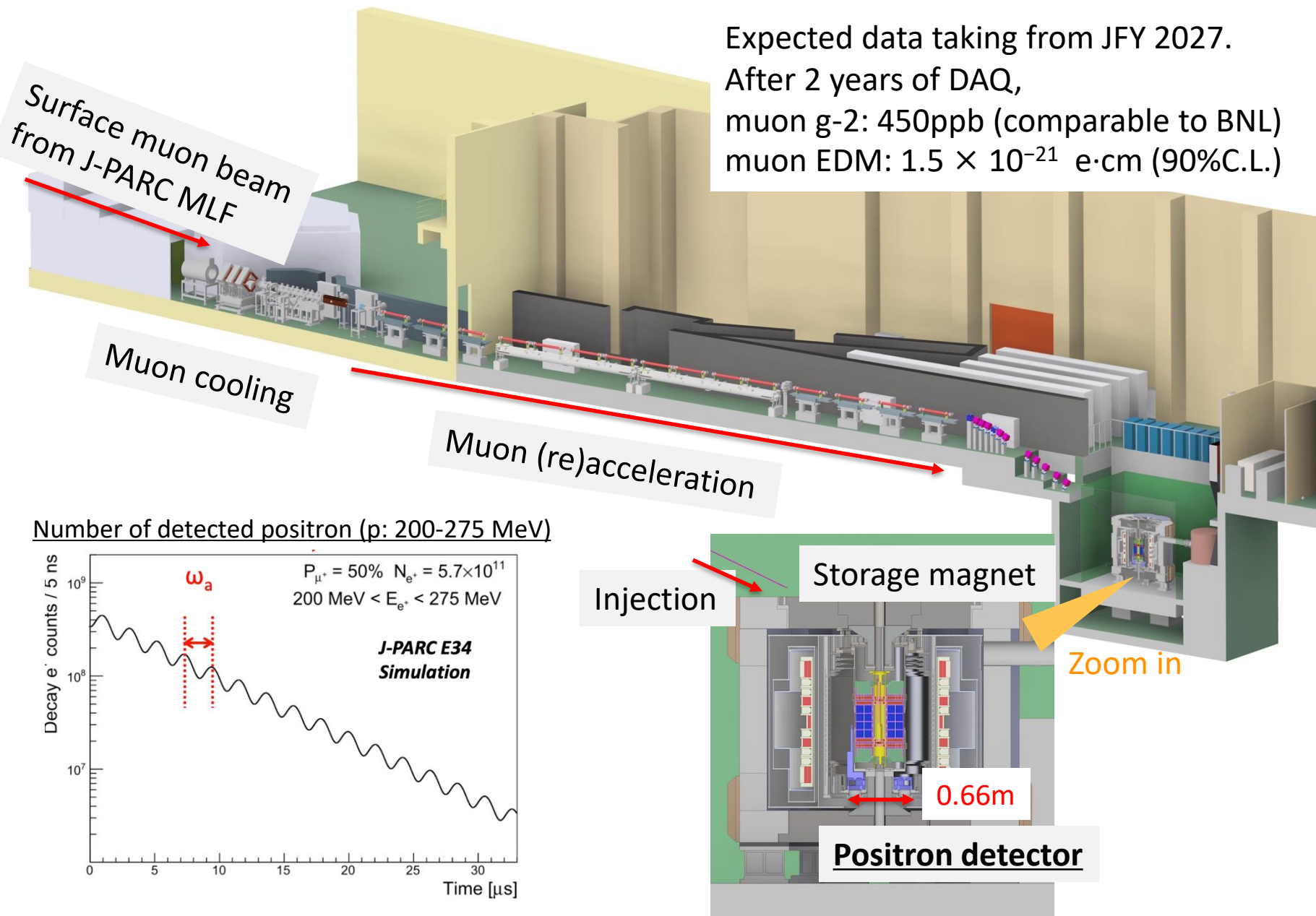
$$\vec{\omega}_a + \vec{\omega}_\eta = -\frac{e}{m_\mu} \left[ a_\mu \vec{B} - \underbrace{\left( a_\mu - \frac{1}{\gamma^2 - 1} \right)}_{g-2} \underbrace{\left( \frac{\vec{\beta} \times \vec{E}}{c} \right)}_{=0} + \frac{\eta}{2} \underbrace{\left( \vec{\beta} \times \vec{B} + \underbrace{\left( \frac{\vec{E}}{c} \right)}_{=0} \right)}_{\text{EDM}} \right]$$



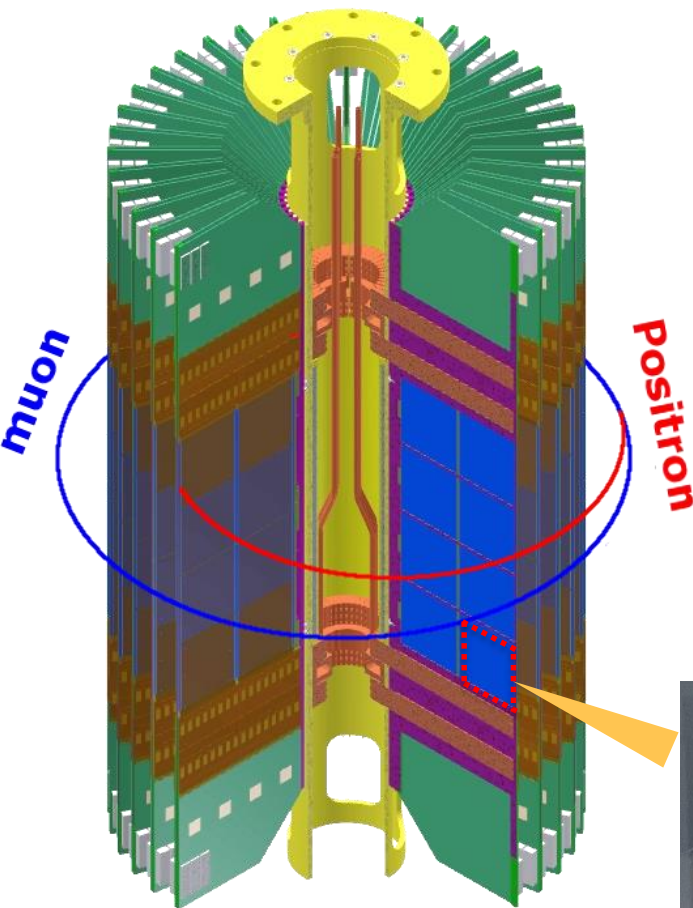
- Measurement at lower muon momentum becomes possible.  
→ More compact storage region with better uniformity of B-field.
  - **p = 0.3 GeV/c, ϕ: 0.66m at B = 3 T**
- Independent measurement of muon g-2 to validate BNL/FNAL result at different systematic uncertainty.
- Clear separation of g-2 and EDM signal.

# Muon g-2/EDM experiment at J-PARC

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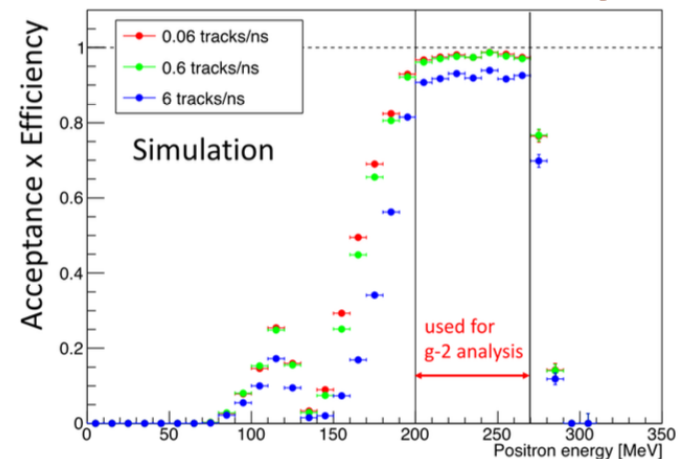
## Silicon strip positron detector for J-PARC muon g-2/EDM experiment

- Compact positron tracking detector by silicon strip sensors (640 100x100 mm<sup>2</sup> sensors).
- High hit rate capability (6 tracks/ns) and stability over rate changes (1.4 MHz → 10 kHz)
- High efficiency for positrons in the analysis window ( $p=200\text{--}275$  MeV/c).
- Operation in vacuum, 3T B-field.
- No EM-field contamination for muon orbit.



HPK S13804  
- single-sided  
silicon strip detector  
- 190um strip

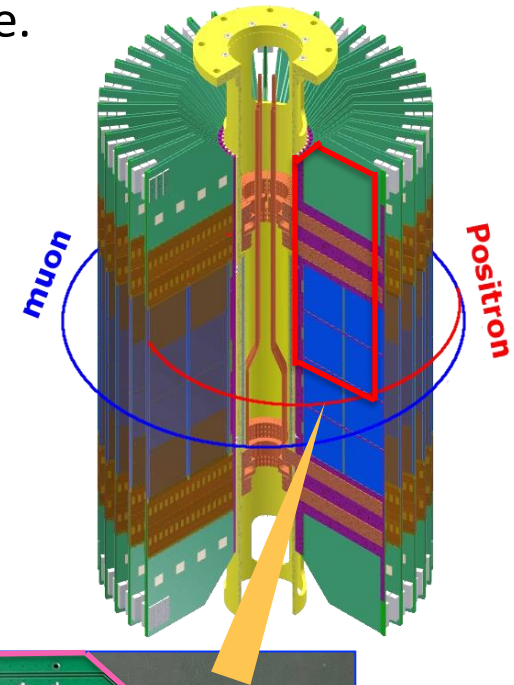
## Reconstruction efficiency



# Silicon strip positron detector

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- Detector consists of 160 submodules called quarter-vane.
- Each quarter-vane consists of
  - Silicon sensor
  - FPC for analog signal transmission
  - ASIC for signal amplification/digitization
  - FPGA board for data/clock communication
  - Cooling system for cooling in vacuum
  - GFRP frame for assembly

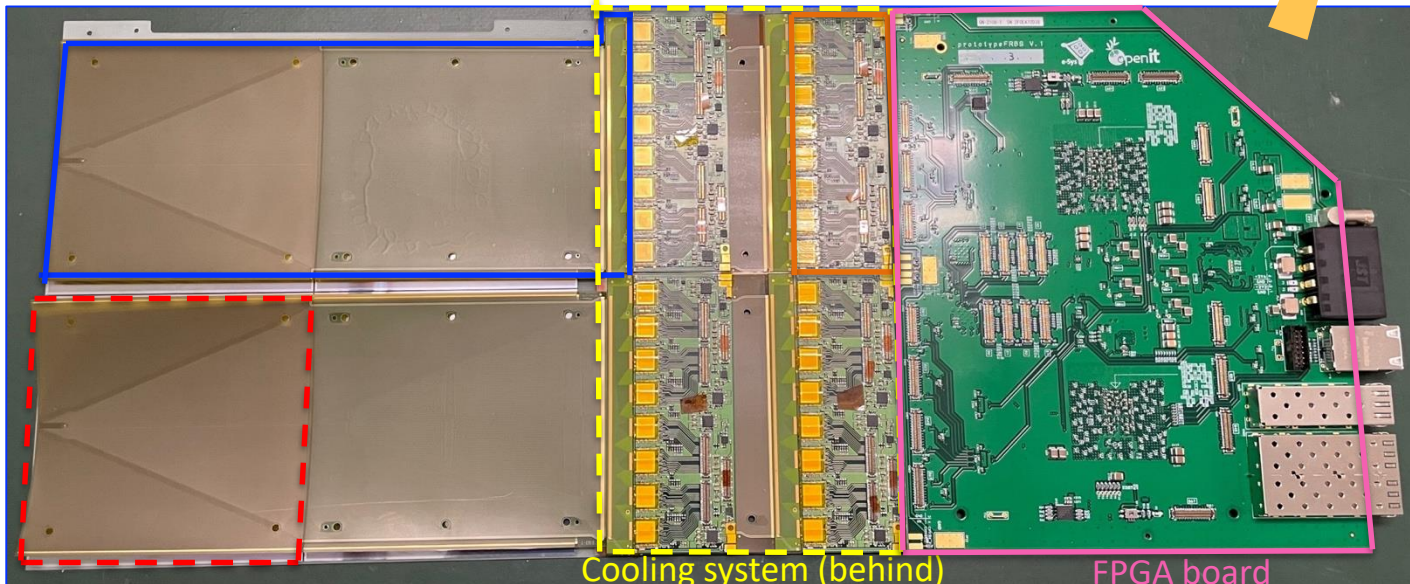


## Quarter-vane: submodule of detector

Sensor FPC & pitch adapter

ASIC & ASIC board

Silicon sensor  
(behind)



Cooling system (behind)

FPGA board

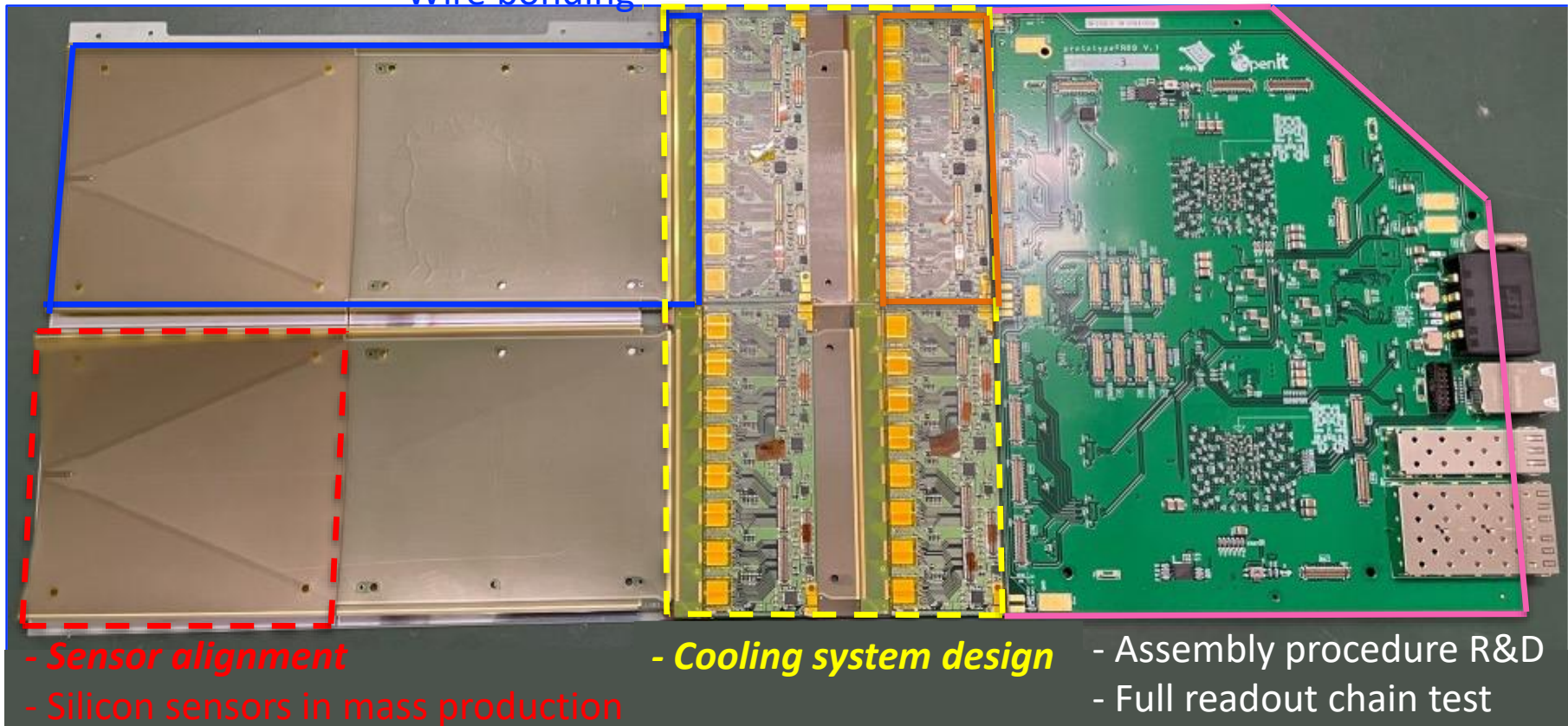


# Silicon strip positron detector

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- Prototyping of quarter-vane is ongoing towards real detector assembly.  
In my talk, three topics are picked up from many R&D activities.

- QA of produced ASICs
- ASIC board development
- Wire bonding
- FPGA board development
- DAQ backend development

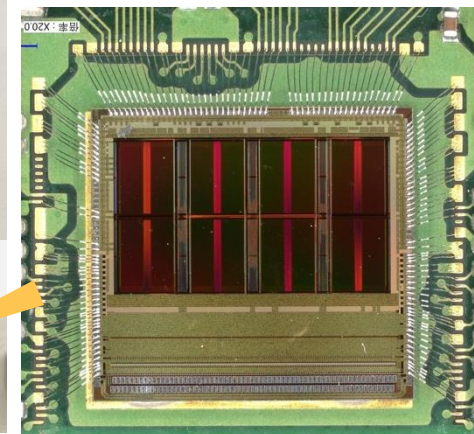
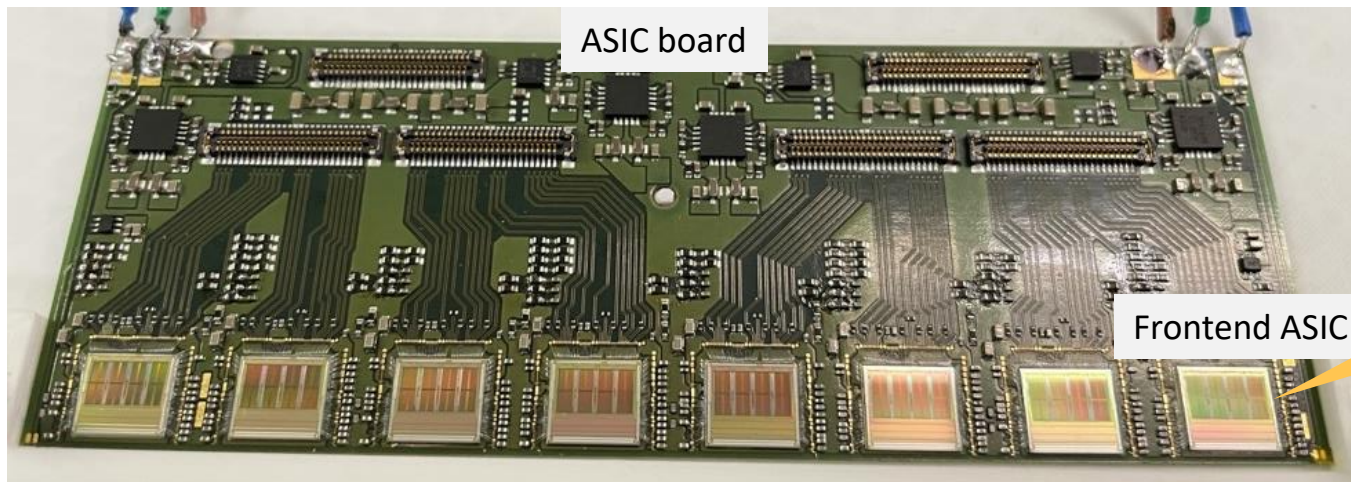
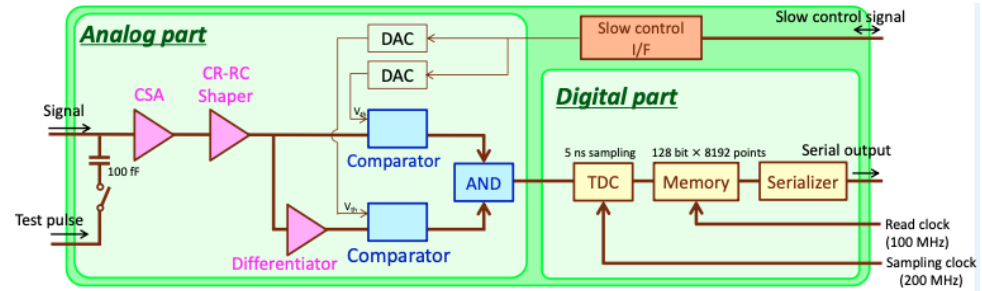




- Frontend ASIC "Slit128D" has been developed for amplification, digitization of silicon sensor signal.

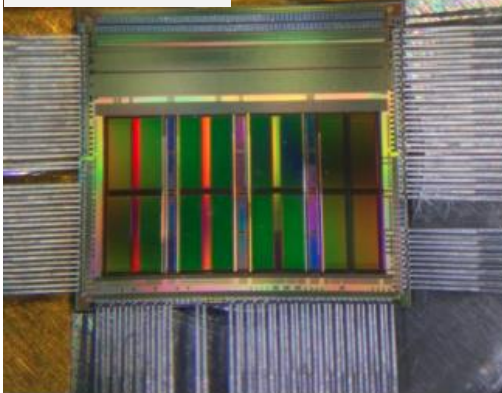
- Slit128D

- SilTerra 180 nm CMOS technology
- Fast response to tolerate a high hit rate
- Readout sequence dedicated for pulsed muon beam at J-PARC
  - 40us measurement period for each 25Hz pulsed beam
  - Binary readout with 5 ns time stamp and large memory buffer

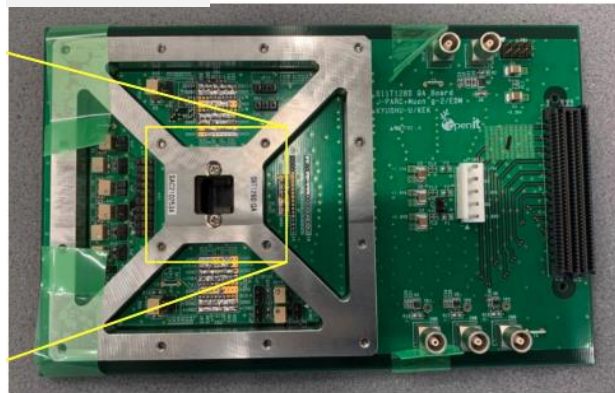


- 15000 ASICs are produced for real detector assembly.
- Quality assurance (QA) of produced ASICs is on going.
  - QA system prepared: dedicated probe card & manual probe station.

Probed ASIC



Probe card



Probe station



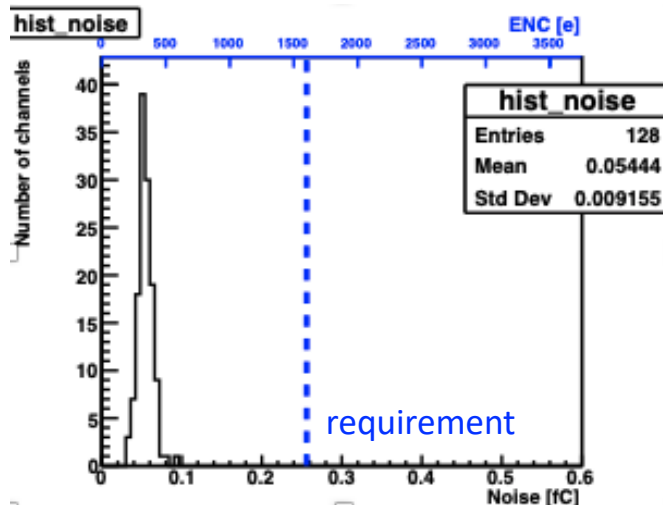
- Performance check to reject bad chip before detector assembly.
  - Power consumption, dead channel, gain, noise, and timewalk are measured.

- So far 62 chips are tested.
  - 10 bad chips (noisy channel etc..) are identified and rejected.

## Noise

- Estimated from “S-curve scan”.
  - voltage threshold scan for the signal of fixed charge
- Requirement:  $ENC < 1600 e^-$

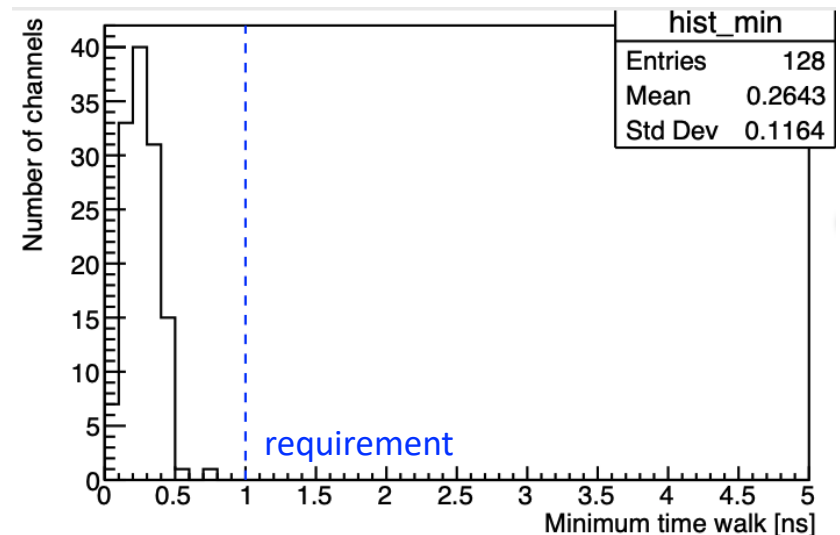
### Noise of each channel (a good chip)



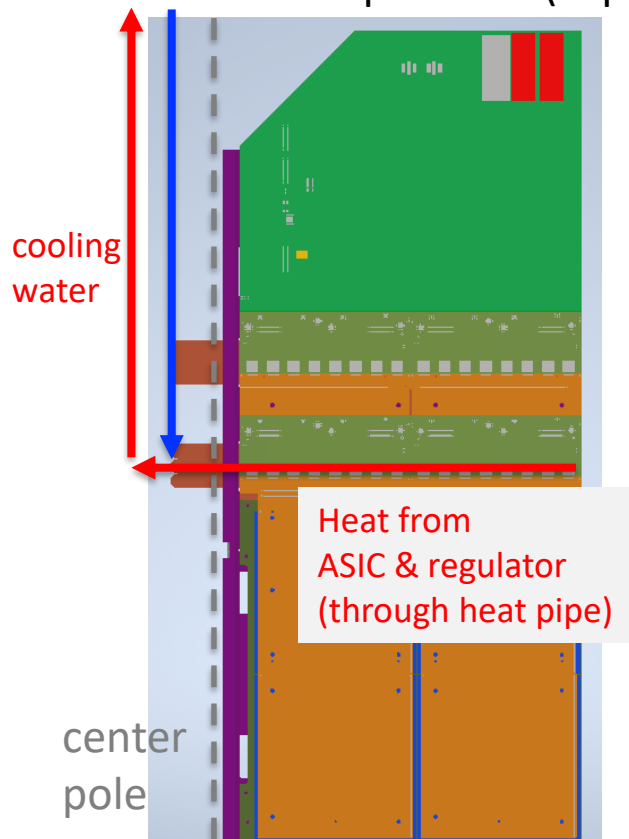
## Timewalk

- Time difference of signal btw/ 0.5 - 3MIP
- Requirement:  $< 1ns$ 
  - large timewalk can deteriorate high rate tolerance, and can lead to a systematic uncertainty of g-2.

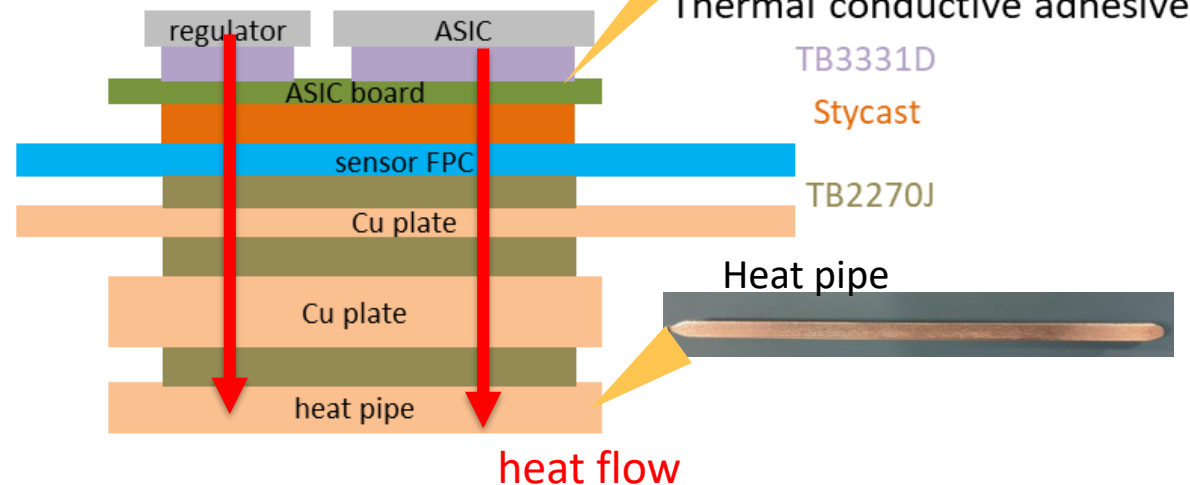
### Timewalk of each channel (a good chip)



- Detector is operated inside vacuum, thus cooling of frontend ASIC, FPGA, regulator etc... is required.
  - In total 5 kW (~30 W per quarter vane) has to be cooled.
- Electric parts are thermally connected to heat pipe, which is cooled down by colling water inside the center pole.
  - ASIC temperature (expectation by FEA): up to 40 deg



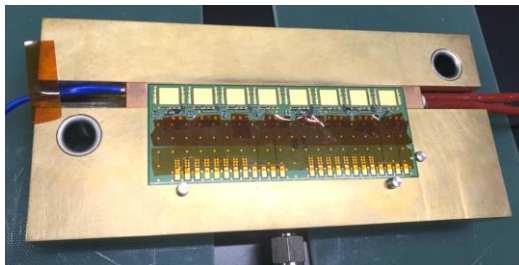
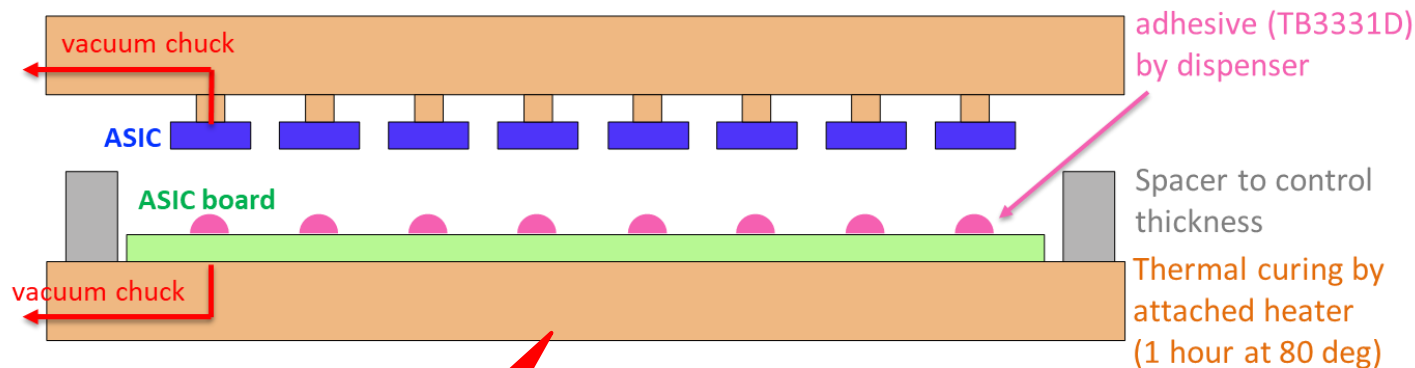
Quarter-vane (simplified cross view)



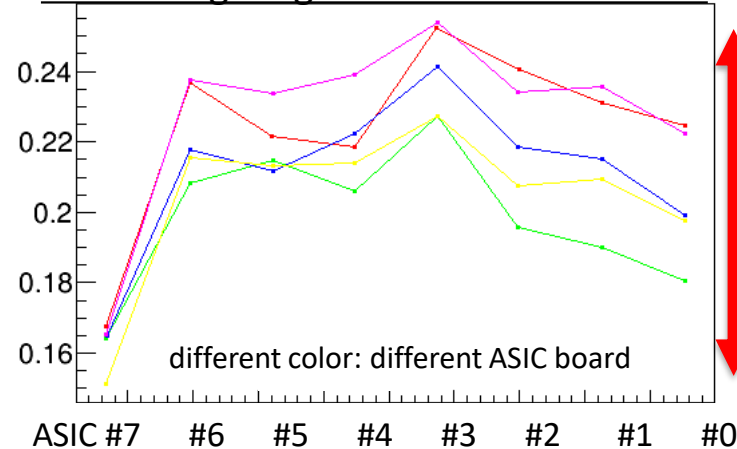


- Assembly procedure to realize this design has been studied.
- Thickness of thermal conductive adhesive has to be well controlled.
  - positioning of work to be glued & control of used amount adhesive
- A dedicated jig to control thickness of adhesive.

ASIC gluing jig (side view)

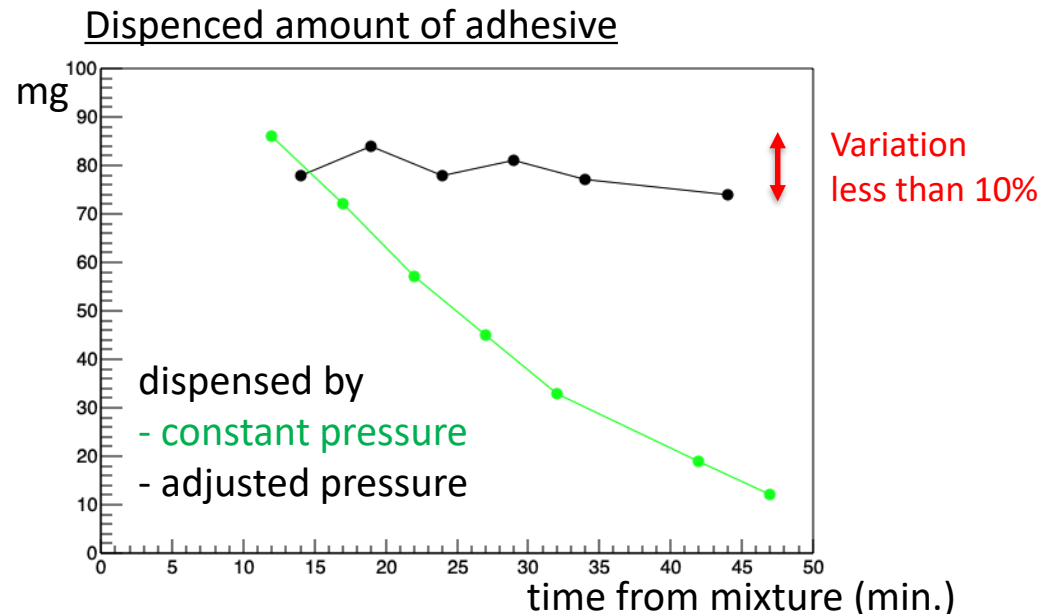
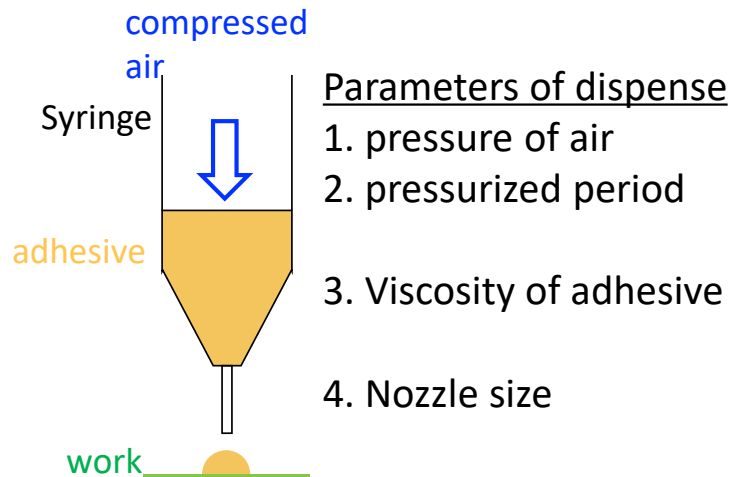


Achieved gluing thickness of each ASIC



thickness  
 $200 \pm 50 \mu\text{m}$

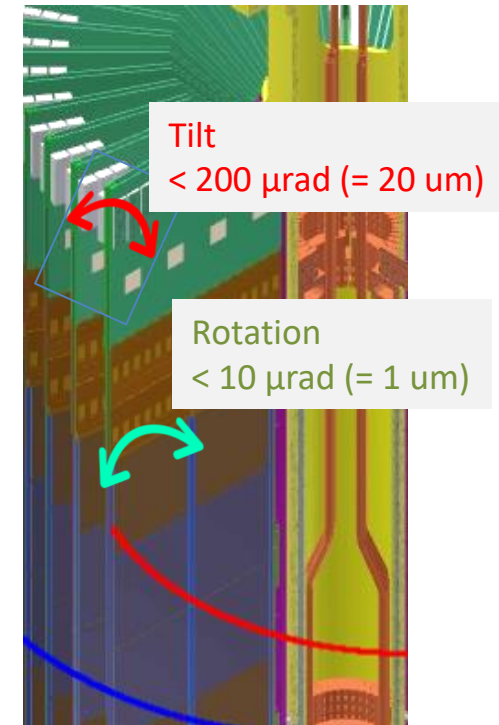
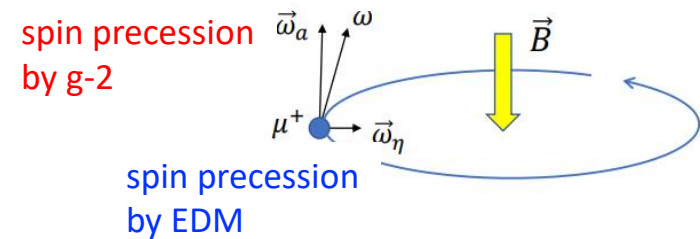
- Amount of adhesive can be controlled by using “dispenser”.
  - adhesive in syringe pushed by compressed air of a given pressure.
  - major parameter : applied pressure & adhesive viscosity
- For two component adhesive (e.g. stycast, araldite), viscosity depends on the speed of chemical reaction, whose direct control is difficult.
- A test dispense on a junk sample just before dispense on the real work
  - Individual difference of amount of adhesive can be reduced.
  - Pressure for real dispense is adjusted, from the amount of adhesive in test dispense.



- Precise alignment between detector and B-field is essential for muon EDM measurement.
  - nonzero EDM can be detected as an up-down asymmetry of number of decay positrons.
  - If rotated each other, “g-2 component” of spin precession comes into “EDM component”.
- Goal of sensor alignment:
  - 10 urad rotation & 200urad tilt.
  - This corresponds to
    - 1 um rotation & 20 um tilt of each sensor.
- Precise positioning of sensors in detector assembly + precise position monitoring of sensor in data taking.

$$\vec{\omega}_a + \vec{\omega}_\eta = -\frac{e}{m} \left[ \frac{g-2}{2} \vec{B} + \frac{\eta}{2} \vec{\beta} \times \vec{B} \right]$$

g-2                      EDM

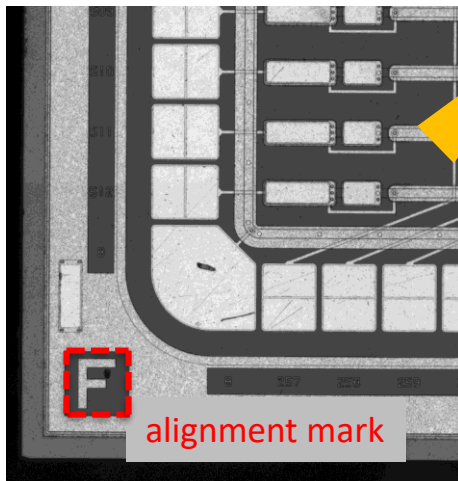


- Silicon sensors are glued on GFRP frame. Gluing procedure with an alignment of  $O(1)$   $\mu\text{m}$  precision is under development.
- CMM (3D coordinate measuring machine) in temperature control room
  - sensor position & shape measurement by  $1\mu\text{m}$  precision
  - temperature is kept to  $20 \pm 1$  deg. , to avoid thermal expansion.

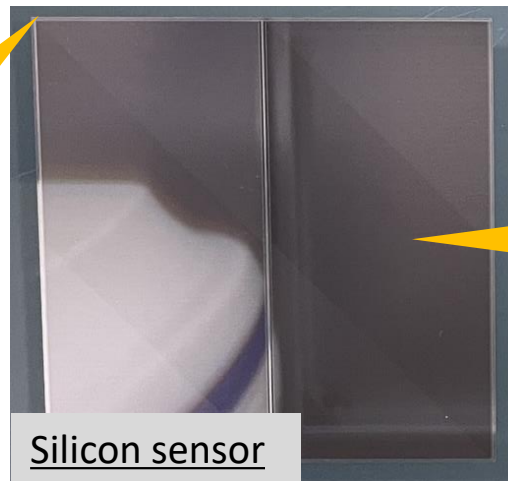
Temperature control room



*Sensor position measurement  
by alignment marker*

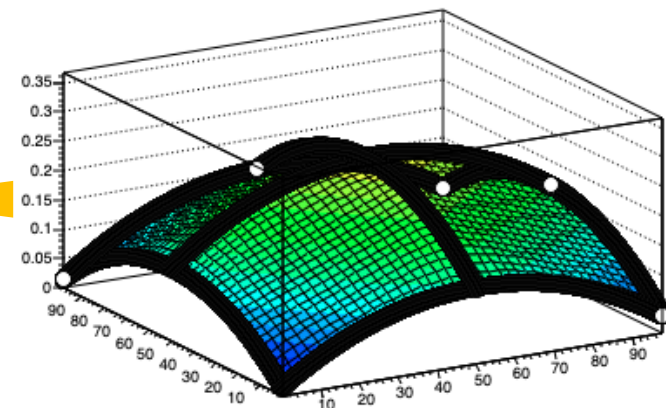


alignment mark



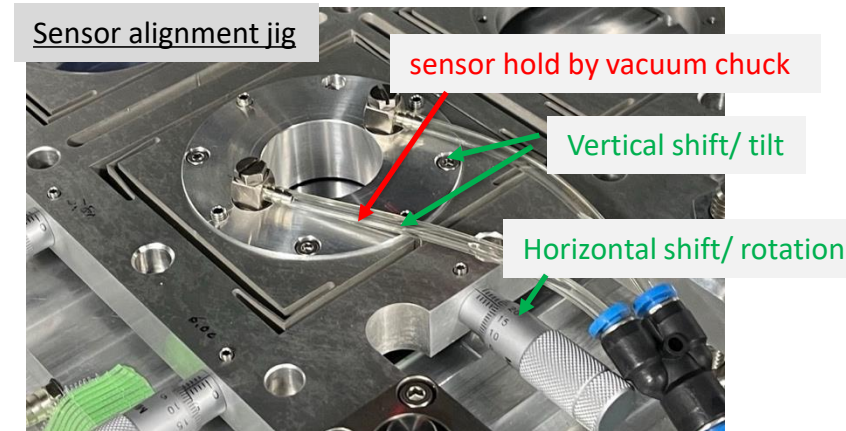
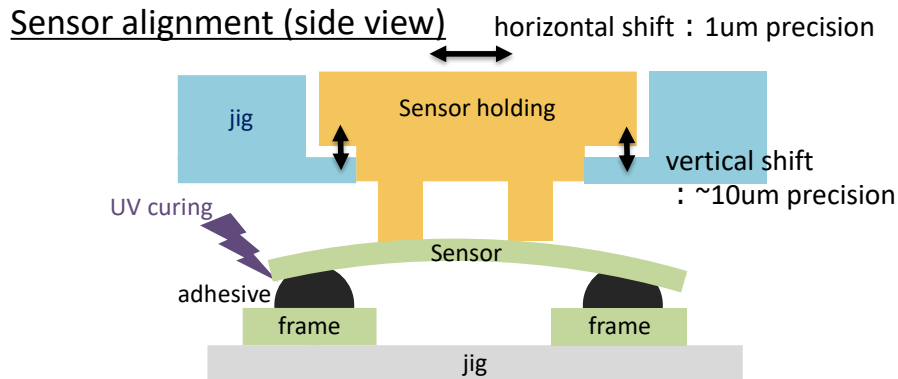
Silicon sensor

*Shape measurement  
by chromatic confocal sensor*





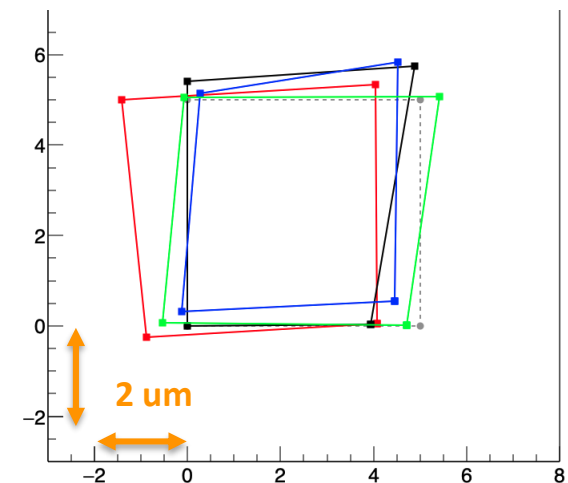
- Sensor positioning by a dedicated jig.
  - Horizontal shift (1 $\mu$ m step) & Vertical shift ( $\sim$ 10  $\mu$ m step)
  - Gluing by a UV curing adhesive.



- Precision better than 2 $\mu$ m is achieved for rotation in quarter-vane plane.
  - already near to the final goal of 1  $\mu$ m



Glued position of each sensor (1<sup>st</sup>, 2<sup>nd</sup>, 3<sup>rd</sup>, 4<sup>th</sup>)  
Deviation from ideal (gray) position



- Silicon strip detector for J-PARC muon g-2/EDM experiment is being developed.
  - Aims to measure muon g-2 with an independent strategy from BNL/FNAL experiments.
- Prototyping of detector submodule (quarter-vane) is ongoing.
  - Frontend ASIC has been produced. Their quality assurance has started.
  - Cooling system has been designed.  
Assembly procedure to control adhesive thickness has been established.
  - Precise sensor alignment for EDM measurement under R&D.  
Precision of 2  $\mu\text{m}$  is already achieved.
- Detector assembly from JFY 2024, and physics data-taking from JFY 2027.

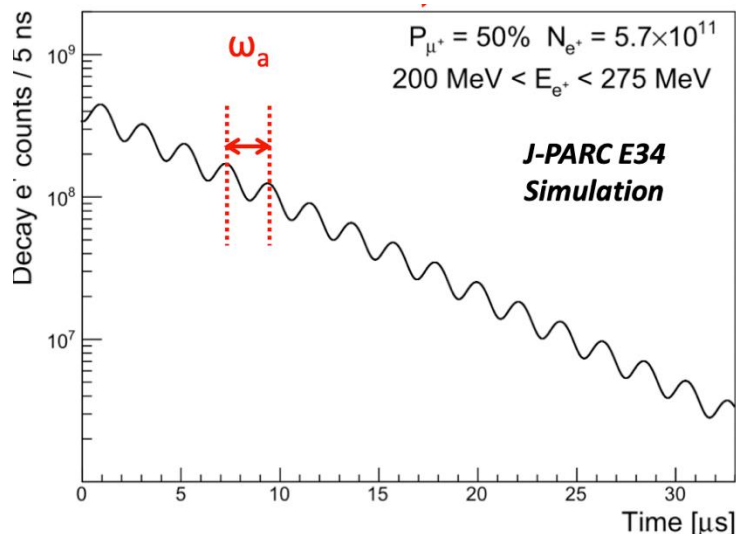
**BACKUP**

## J-PARC experiment

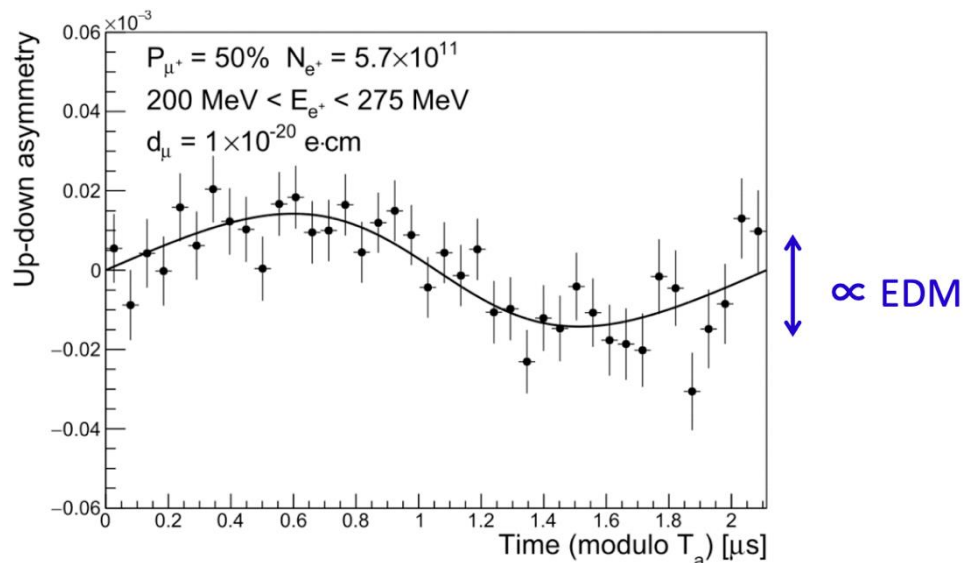
- Measurement at  $\vec{E} = 0$ .
  - Storage by weak focusing B-field
  - Utilize low emittance muon beam.

$$\vec{\omega}_a + \vec{\omega}_\eta = -\frac{e}{m_\mu} \left[ \underbrace{a_\mu \vec{B}}_{g-2} - \left( a_\mu - \frac{1}{\gamma^2 - 1} \right) \underbrace{\frac{\vec{\beta} \times \vec{E}}{c}}_{=0} + \underbrace{\frac{\eta}{2} \left( \vec{\beta} \times \vec{B} + \frac{\vec{E}}{c} \right)}_{\text{EDM}} \right]$$

Number of detected positron (p: 200-275 MeV)



Up-down asymmetry of detected positron

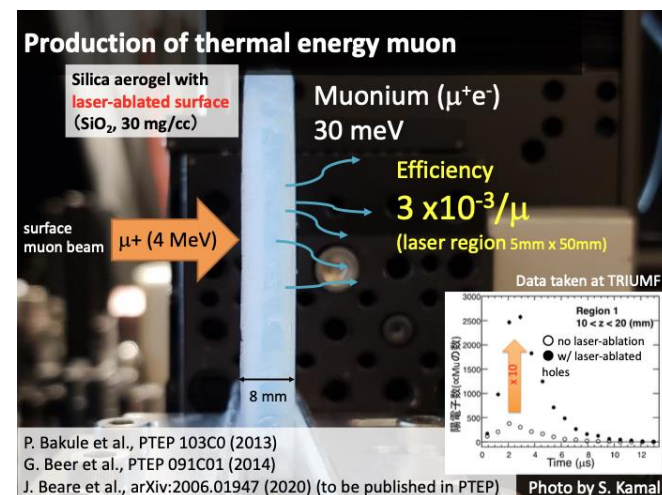
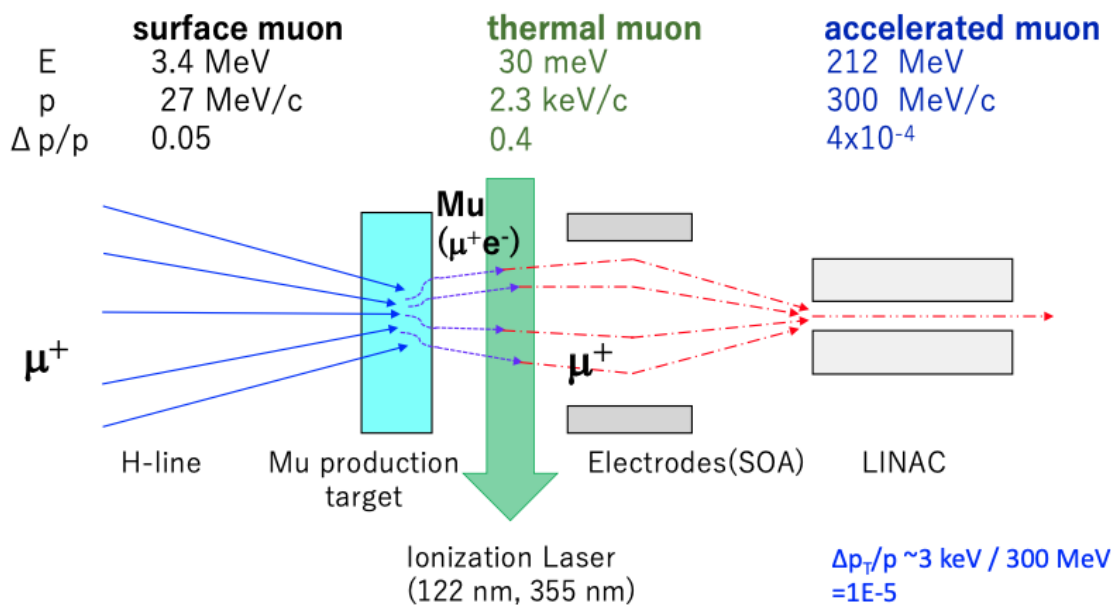




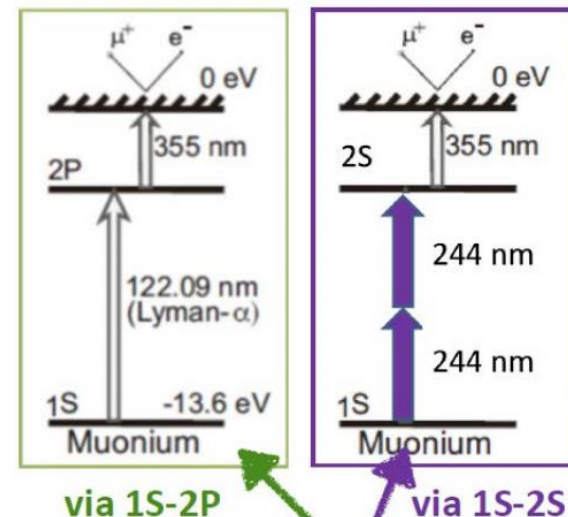
# Muon cooling

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- Low emittance muon beam by reacceleration of thermal muon.
  - Silica aerogel target : Surface muons stopped, and thermal muoniums emitted.
  - Laser ablated aerogel to increase the efficiency.



- Thermal muonium ionization by laser.
  - Two scheme under consideration.
  - 1S-2P excitation by 122nm or 1S-2S excitation by 244nm



Physics data taking expected from JFY 2027.

	2021	2022	2023	2024	2025	2026	2027 and beyond
KEK Budget							
Surface muon		★ Beam at H1 area		★ Beam at H2 area			
Bldg. and facility			★ Final design			★ Completion	
Muon source		★ Ionization test @S2		★ Ionization test at H2			
LINAC			★ 80keV acceleration@S2	★ 4.3 MeV@ H2		★ fabrication complete	★ 210 MeV
Injection and storage			★ Completion of electron injection test				★ muon injection
Storage magnet				★ B-field probe ready		★ Install	★ Shimming done
Detector		★ Quater vane prototype	★ Mass production ready			★ Installation	
DAQ and computing		★ grid service open	★ small DAQ system	★ common computing operation test	★ Ready		
Analysis				★ Tracking software ready		★ Analysis software ready	

Commissioning

Data taking

- Total efficiency of muon will be  $1.3 \times 10^{-4}$ .

Subsystem	Efficiency	Subsystem	Efficiency
H-line acceptance and transmission	0.16	DAW decay	0.96
Mu emission	0.0034	DLS transmission	1.00
Laser ionization	0.73	DLS decay	0.99
Metal mesh	0.78	Injection transmission	0.85
Initial acceleration transmission and decay	0.72	Injection decay	0.99
RFQ transmission	0.95	Kicker decay	0.93
RFQ decay	0.81	$e^+$ energy window	0.12
IH transmission	0.99	Detector acceptance of $e^+$	1.00
IH decay	0.99	Reconstruction efficiency	0.90
DAW transmission	1.00		

## Muon g-2

- Statistical uncertainty: 450 ppb (2 years of data taking)
  - Uncertainty comparable to BNL can be reached
- Systematic uncertainty: less than 70 ppb.

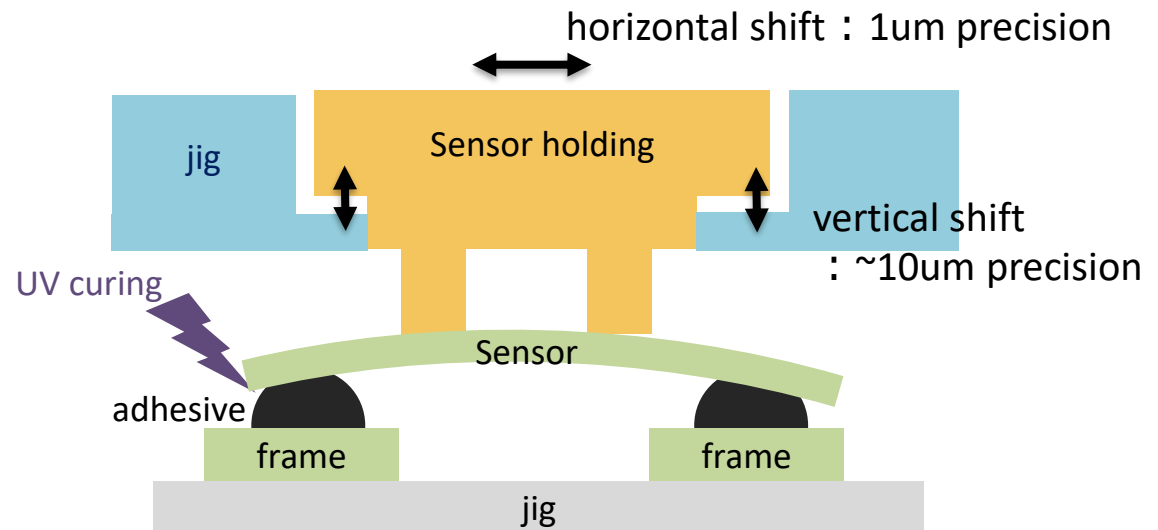
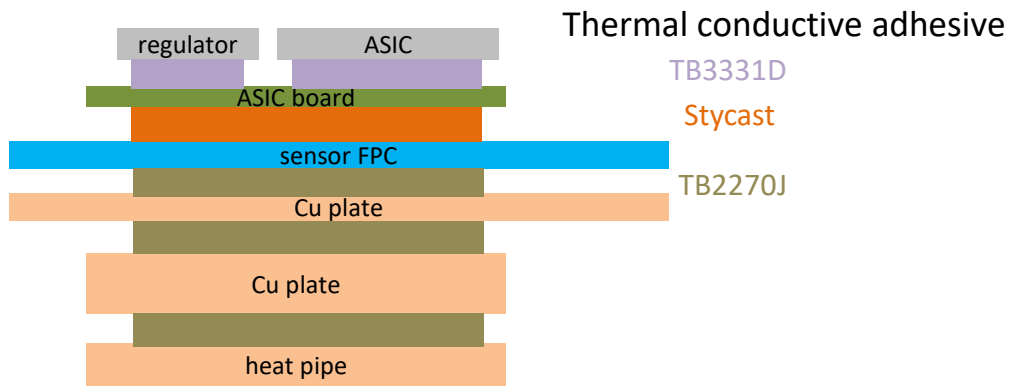
Anomalous spin precession ( $\omega_a$ )		Magnetic field ( $\omega_p$ )	
Source	Estimation (ppb)	Source	Estimation (ppb)
Timing shift	< 36	Absolute calibration	25
Pitch effect	13	Calibration of mapping probe	20
Electric field	10	Position of mapping probe	45
Delayed positrons	0.8	Field decay	< 10
Differential decay	1.5	Eddy current from kicker	0.1
Quadratic sum	< 40	Quadratic sum	56

## Muon EDM

- Statistical uncertainty:  $1.5 \times 10^{-21} \text{ e} \cdot \text{cm}$
- Systematic uncertainty:  $0.4 \times 10^{-21} \text{ e} \cdot \text{cm}$ 
  - mainly from detector mis-alignment

- a

Quarter-vane (simplified cross view)





### ASIC gluing jig (side view)

